

<b>Notice of References Cited</b>	Application/Control No. 10/825,529	Applicant(s)/Patent Under Reexamination BORODITSKY ET AL.	
	Examiner Christina Y. Leung	Art Unit 2613	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,563,590 B2	05-2003	Chowdhury et al.	356/484
*	B	US-6,885,783 B2	04-2005	Bandemer et al.	385/11
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 200167649 A1	09-2001	World Intellect	BANDEMER et al.	
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	IEEE Xplore AbstractPlus corresponding to Boroditsky, M. et al. "In-service measurements of polarization-mode dispersion and correlation to bit-error rate."
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.